Advanced Computer-Aided VLSI System Design

Homework 3: Keccak Hash Function

Graduate Institute of Electronics Engineering, National Taiwan University



Goals



- In this homework, you will learn
 - How to insert scan chain
 - How to design and implement a small scale BIST
 - How to combine the learned techniques (optional)

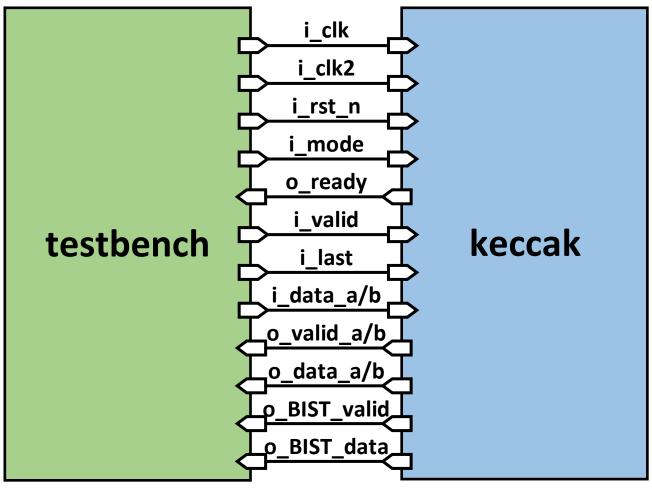
Introduction



- Keccak hash function is the precursor to the well-known SHA-3 hash function.
- Cryptographic hash functions like this can generate deterministic, collision-resistant and irreversible output from arbitrary input data.
- They are wildly used in secure applications such as encryption, authentication and digital signature.

Block Diagram





Input/Output



Signal Name	I/O	Width	Simple Description
i_clk	I	1	Clock for IO All inputs and outputs are synchronized with the positive edge with 0.5 ns of input and output delay
i_clk2	I	1	Optional clock for computational core
i_rst_n	I	1	Active low asynchronous reset.
i_mode	ſ	2	Operation mode selection
o_ready	0	1	Pull high if ready for next input

Input/Output



Signal Name	I/O	Width	Simple Description	
i_valid	I	1	Pull high if input data is valid	
i_last	I	1	Pull high if this is the last part of current input sequence	
i_data_a	I	128	Input data A if i_valid is high; otherwise, all X's	
i_data_b	I	128	Input data B if i_valid is high; otherwise, all X's	
o_valid_a	0	1	Pull high if output data A is valid	
o_data_a	0	64	Output data A	

Input/Output



Signal Name	I/O	Width	Simple Description	
o_valid_b	0	1	Pull high if output data B is valid	
o_data_b	0	64	Output data B	
o_BIST_valid	0	1	Pull high if BIST output is valid	
o_BIST_data	0	64	Output of BIST mode	

Specification



- Active low asynchronous reset is used only once
- There should be at least one scan chain in your design
- The total simulation time for each public case must not exceed
 6000 ns
- The synthesis result should NOT include any latch
- There should be NO timing violations in the gate-level simulation after first positive edge of i clk after reset

Operation Mode



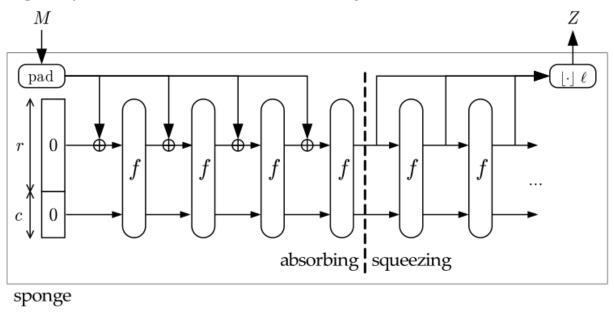
There are three operation modes

Mode	Code	Description	
Single	2'b00	Compute Keccak hash for only input A	
Double	2'b01	Compute Keccak hash for both input A and input B separately	
BIST	2'b11	Perform built-in self-test	

Keccak Hash Function



- Keccak is a family of hash functions that is based on sponge construction
- Sponge construction = absorbing phase + squeezing phase
- Variable-length input and arbitrary output length based on a fixed-length permutation function f



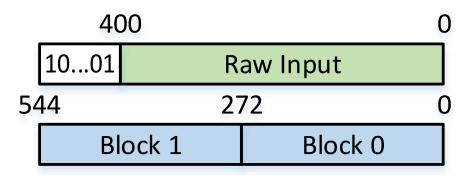
Keccak Hash Function



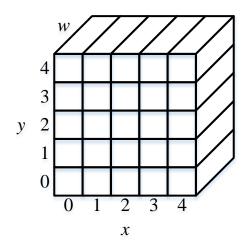
 In this homework, you are asked to implement a variant of the Keccak hash function with the following parameters

Parameter	Value	Parameter	Value
l	4	$w = 2^l$	16
$b = 25 \times w$	400	С	128
r = b - c	272	Rounds = $12 + 2l$	20
Input length	Nr	Output length	64

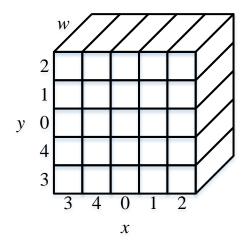
- 1. Padding: Pad the raw input to an input sequence whose length is aligned with *r*
 - Padding rule: append a single bit 1, followed by zero or more 0's, and end with a single bit 1
 - Done by TA in software
 - Note: byte to int conversion adopt little-endian



- 2. Initialization: Initialize the state S as an empty array
 - Shape: $5 \times 5 \times w$



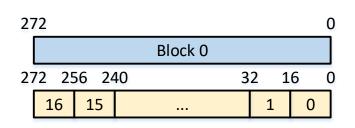
Suitable for implementation

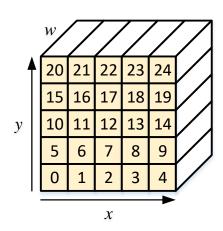


Suitable for understanding

3. Absorbing: Consume input data

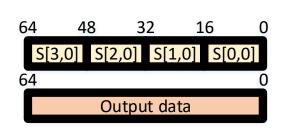
```
for B in Blocks
  for y in 0 ... 4
    for x in 0 ... 4
    if [(x+5*y) < r/w]
        S[x,y] = S[x,y] xor B[(x+5*y)*w +: w]
    S = Keccak-f(S)</pre>
```

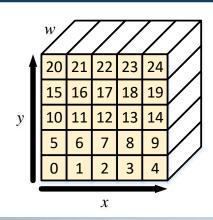




4. Squeezing: Output hash result

```
Z = ""
while [output_len > 0]
  for y in 0 ... 4
    for x in 0 ... 4
    if [(x+5*y) < r/w] and [output_len > 0]
        Z = Z || S[x,y]
  if [output_len > 0]
    S = Keccak-f(S)
```

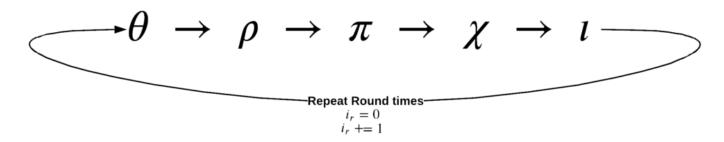




Keccak-f



- Keccak-f is the underlying permutation function for Keccak
- There are 20 rounds in the chosen variant
- Each round consists of 5 different steps

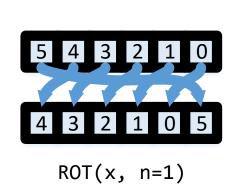


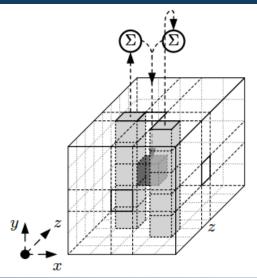
$$Rounds = 12 + 2\ell$$



1. θ step: Diffusion across the state array

```
for x in 0 ... 4
   C[x] = S[x,0] xor S[x,1] xor ... S[x,4]
for x in 0 ... 4
   D[x] = C[(x-1)%5] xor ROT(C[(x+1)%5], 1)
   for y in 0 ... 4
   S[x,y] = S[x,y] xor D[x]
```



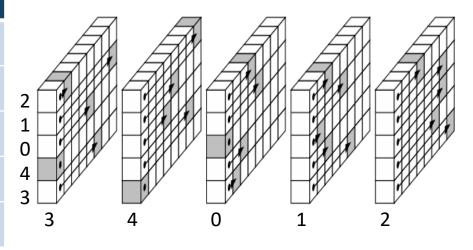




2. ρ step: Bitwise rotation

```
for y in 0 ... 4
  for x in 0 ... 4
  S[x,y] = ROT(S[x,y], OFFSET[x,y])
```

OFFSET	x = 0	x = 1	x = 2	x = 3	x = 4
y = 0	0	1	14	12	11
y = 1	4	12	6	7	4
y = 2	3	10	11	9	7
y = 3	9	13	15	5	8
y = 4	2	2	13	8	14





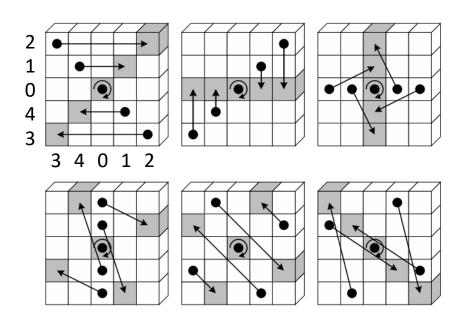
3. π step: Dispersion for long-term diffusion

```
for y in 0 ... 4

for x in 0 ... 4

S'[y,(2x+3)%5] = S[x,y]

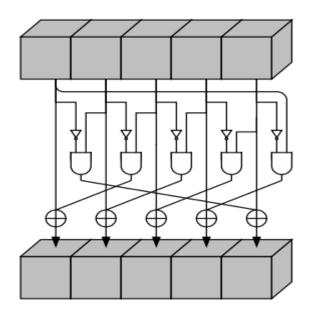
S = S'
```





4. χ step: Nonlinear transformation

```
for y in 0 ... 4
  for x in 0 ... 4
    S'[y,x] = S[x,y] xor [(not S[(x+1)%5,y]) and S[(x+2)%5,y]]
S = S'
```





5. ι step: Disrupt symmetry

$$S[0,0] = S[0,0] \times RC[round_idx]$$

Round	RC	Round	RC	Round	RC	Round	RC
0	0x0001	5	0x0001	10	0x8009	15	0x8003
1	0x8082	6	0x8081	11	0x000A	16	0x8002
2	0x808A	7	0x8009	12	0x808B	17	0x0080
3	0x8000	8	0x008A	13	0x008B	18	0x800A
4	0x808B	9	0x0088	14	0x8089	19	0x000A

Built-In Self-Test



- BIST can check the correctness of the circuit without external test patterns
- You are asked to implement BIST for all the XOR operations in your design
- All XOR operation must be achieved by instantiating the xor2 module provided by TA

```
1  module xor2 #(
2  parameter ID = 0
3  ) (
4  output [63:0] o_ID,
5  input [ 1:0] a,
6  input [ 1:0] b,
7  output [ 1:0] z
8  );
```

Built-In Self-Test



- Each xor2 instance should be assigned a unique ID through module parameter, ranging from 1 to 2⁶⁴-1
- In BIST mode, the design should check the correctness of all the xor2 instances, and output the ID of the faulty instance
- If all instances are fault-free, o_BIST_data should be assigned 0
- It is guaranteed that there will be at most one faulty instance
- It is guaranteed that the faulty instance will produce wrong output for at least one combination of inputs (total 2⁴ possible combinations)

Scan Chain

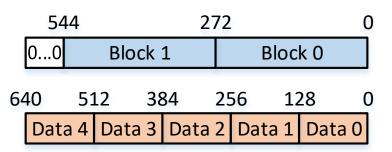


- You must insert at least one scan chain in your design
- All registers must be on the scan chain(s)
- Use dedicate scan out pin
- Check lab3 for details
- It is also encouraged to try ATPG on IC Lab server (optional)

Input / Output



- The operation mode (i_mode) will be stable throughout the entire simulation
- For mode 00 and 01,
 - There will be multiple input sequences in one simulation
 - Each input sequence will be partitioned into [seq_len/128] input data of 128 bits
 - i_last indicates the last part of the current input sequence,
 and will only be pulled high if i_valid is pulled high



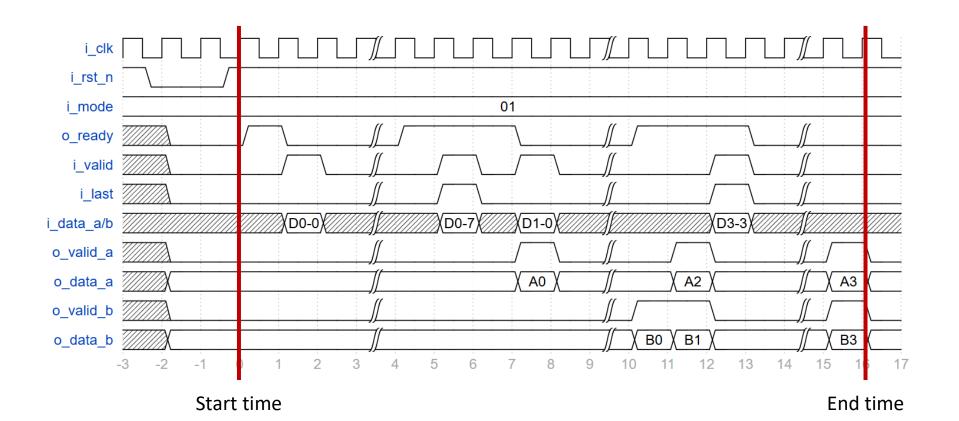
Input / Output



- For mode 00 and 01,
 - If i_valid is low and o_ready is high, i_valid will be randomly pulled high in the next cycle
 - If i_valid is high or o_ready is low, i_valid will be low in the next cycle
 - Output set A and output set B are independent
 - Output data must be in the same order of input data
 - o_valid_a/b can be pulled high independently at any positive edge of i_clk

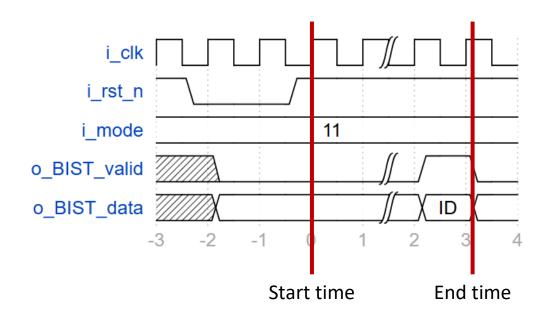
Timing Diagram





Timing Diagram



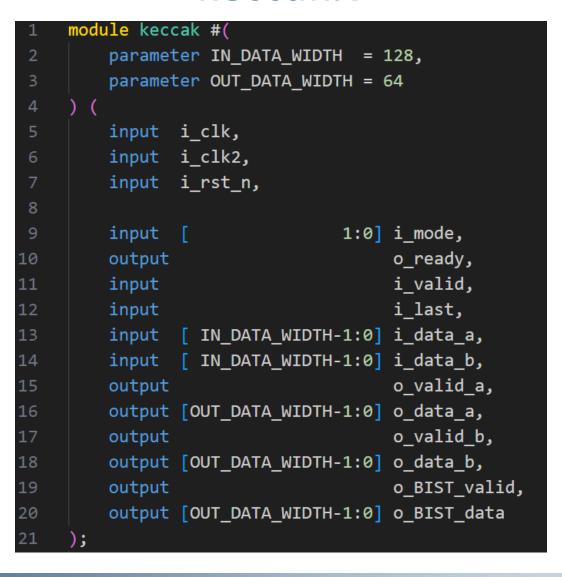


Hint



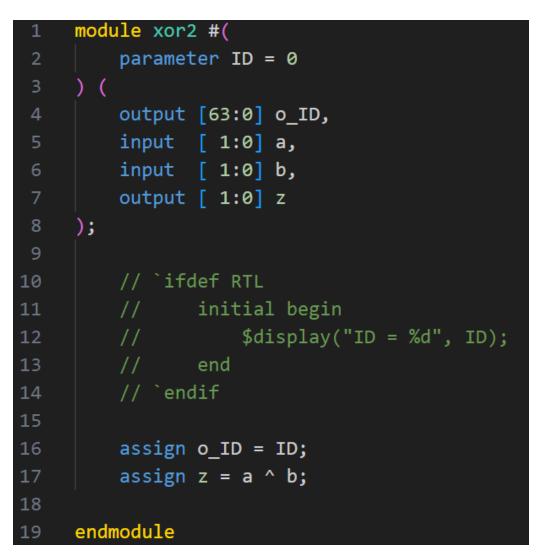
- You may adopt any techniques learned to gain better performance, including clock gating, power gating, multiple clock domain, etc.
- The scripts may not be complete. Remember to modify them.

keccak.v





xor2.v





Report



- Total number of xor2 instances in your design
- Clock period for i_clk and i_clk2
- Area after scan chain insertion
- Gate-level (including scan chain) runtime and power for each public pattern

Submission



Create a folder named studentID_hw3 and follow the hierarchy below

- Pack the folder studentID_hw3 into a tar file named studentID_hw3_vk.tar (k is the number of version, k =1,2,...)
- Submit to NTU Cool and place the tared file at your home dir

Grading Policy



- TA will use 01_run and 03_run to run your code at RTL and gate-level (including scan chain) simulation. Modify them to your needs.
- Hash function simulation (mode 00 and 01) (50%)
 - 0 point for the test case that takes more than 6000 ns

	Score
RTL public	20%
Gate-level public	20%
Gate-level private	10%

- BIST simulation (mode 11) (10%)
 - Pass both RTL and gate-level simulation to get full points
 - Otherwise, 0 point

Grading Policy



- Scan chain insertion (10%)
 - Report files generated by design compiler
- Performance ranking (30%)
 - You may get this score only if you get full points in all the above criteria

Score =
$$A \times (T_{00} \times P_{00} + T_{01} \times P_{01} + T_{11} \times P_{11})$$

A: Total cell area after scan chain insertion (um²)

 T_x : Simulation time of mode x reported by testbench (ns)

 P_x : Average power of mode x reported by primetime (mW)

Grading Policy



- Do not memorize the answers directly in any way
- Lose 10 points for any violation of design specifications
- Lose 5 points for any wrong naming rule or format for submission
- No delay submission is allowed
- No plagiarism

References



- [1] The Keccak Reference https://keccak.team/files/Keccak-reference-3.0.pdf
- [2] In-depth Visual Breakdown of the SHA-3 Cryptographic Hashing Algorithm https://chemejon.io/sha-3-explained
- [2] Synopsys ® Multivoltage Flow User Guide
- [3] R. Ginosar, Metastability and Synchronizers: A Tutorial, 2011.
- [4] Clifford E. Cummings, Clock Domain Crossing (CDC) Design & Verification Techniques Using SystemVerilog, 2008.